RELIABILITY REPORT

FOR

MAX6613MXK

PLASTIC ENCAPSULATED DEVICES

June 10, 2003

MAXIM INTEGRATED PRODUCTS

120 SAN GABRIEL DR.

SUNNYVALE, CA 94086

Written by

Jim Pedicord
Quality Assurance
Reliability Lab Manager

Reviewed by

Bryan J. Preeshl
Quality Assurance
Executive Director

Conclusion

The MAX6613 successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

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I. Device Description

The MAX6613 is a low-power analog precision analog output temperature sensor in a tiny 5-pin SC70 package. The MAX6613 operates over a supply voltage range of 1.8V to 5.5V, with a typical current consumption of only 7.5µA. It is particularly well suited for portable applications where minimizing battery cost and maximizing useful battery life are crucial.

The MAX6613 provides an analog voltage output proportional to temperature. Accuracy is ±1.3°C (max) over a range of T_A = 0°C to +50°C and ±2.0°C (max) from T_A = -20°C to +80°C. Self-heating effects are negligible due to the low current consumption of the part.

Unlike many analog temperature sensors, the MAX6613 is stable with any capacitive load from 0pF to 1000pF, providing broad flexibility in board-level design.

The operating temperature range varies with the voltage supply. The MAX6613 can be used over a range of -55°C to +130°C with a supply voltage of 2.5V to 5.5V. For applications with a supply voltage of 1.8V, the MAX6613 can be used over a temperature range of +25°C to +130°C.

B. Absolute Maximum Ratings

Item	Rating
(All Voltages Referenced to GND, Unless Otherwise Noted.)	
VCC to GND	-0.3V to +6V
All Other Pins to GND	-0.3V to (VCC + 0.3V)
OUT Short to GND	Continuous
Output Current	-1mA to +50mA
ESD Protection (Human Body Model)	2000V
Operating Temperature Range	-55°C to +130°C
Junction Temperature	+150°C
Storage Temperature Range	-65°C to +150°C
Lead Temperature (soldering 10s)	+300°C
Continuous Power Dissipation (TA = +70°C)	
5-Pin SC70	247mW
Derates above +70°C	
5-Pin SC70	3.1mW/°C

II. Manufacturing Information

A. Description/Function:	Low-Voltage Analog Temperature Sensor in an SC70 Package
B. Process:	S8
C. Number of Device Transistors:	1346
D. Fabrication Location:	Oregon, USA
E. Assembly Location:	Malaysia
F. Date of Initial Production:	April, 2002

III. Packaging Information

A. Package Type:	**5-Lead SC70**
B. Lead Frame:	Alloy 42
C. Lead Finish:	Solder Plate
D. Die Attach:	Silver-filled Epoxy
E. Bondwire:	Gold (1.0 mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	Buildsheet # 05-2901-0049
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard JESD22-A112:	Level 1

IV. Die Information

A. Dimensions:	31 x 30 mils
B. Passivation:	Si_3N_4/SiO_2 (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Aluminum/Copper/Silicon
D. Backside Metallization:	None
E. Minimum Metal Width:	.8 microns (as drawn)
F. Minimum Metal Spacing:	.8 microns (as drawn)
G. Bondpad Dimensions:	5 mil. Sq.
H. Isolation Dielectric:	SiO_2
I. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

A. Quality Assurance Contacts:

Jim Pedicord	(Reliablity Lab Manager)
Bryan Preeshl	(Executive Director of QA)
Kenneth Huening	(Vice President)

B. Outgoing Inspection Level: 0.1% for all electrical parameters guaranteed by the Datasheet.
0.1% For all Visual Defects.

C. Observed Outgoing Defect Rate: < 50 ppm

D. Sampling Plan: Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in **Table 1**. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{MTTF} = \frac{1.83}{192 \times 4389 \times 80 \times 2}$$

(Chi square value for MTTF upper limit)

Thermal acceleration factor assuming a 0.8eV activation energy

$\lambda = 13.57 \times 10^{-9}$ $\lambda = 13.57$ F.I.T. (60% confidence level @ 25°C)

This low failure rate represents data collected from Maxim's reliability qualification and monitor programs. Maxim also performs weekly Burn-In on samples from production to assure the reliability of its processes. The reliability required for lots which receive a burn-in qualification is 59 F.I.T. at a 60% confidence level, which equates to 3 failures in an 80 piece sample. Maxim performs failure analysis on lots exceeding this level. The following Burn-In Schematic (Spec. #06-5974) shows the static circuit used for this test. Maxim also performs 1000 hour life test monitors quarterly for each process. This data is published in the Product Reliability Report (**RR-1M**).

B. Moisture Resistance Tests

Maxim evaluates pressure pot stress from every assembly process during qualification of each new design. Pressure Pot testing must pass a 20% LTPD for acceptance. Additionally, industry standard 85°C/85%RH or HAST tests are performed quarterly per device/package family.

C. E.S.D. and Latch-Up Testing

The TS37 die type has been found to have all pins able to withstand a transient pulse of 1000V, per Mil-Std-883 Method 3015 (reference attached ESD Test Circuit). Latch-Up testing has shown that this device withstands a current of ±50mA.

Table 1
Reliability Evaluation Test Results

MAX6613MXK

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES
Static Life Test (Note 1)				
	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	80	0
Moisture Testing (Note 2)				
Pressure Pot	Ta = 121°C P = 15 psi. RH= 100% Time = 168hrs.	DC Parameters & functionality	77	0
85/85	Ta = 85°C RH = 85% Biased Time = 1000hrs.	DC Parameters & functionality	77	0
Mechanical Stress (Note 2)				
Temperature Cycle	-65°C/150°C 1000 Cycles Method 1010	DC Parameters & functionality	77	0

Note 1: Life Test Data may represent plastic D.I.P. qualification lots.
Note 2: Generic package/process data

Attachment #1

TABLE II. Pin combination to be tested. 1/ 2/

	Terminal A (Each pin individually connected to terminal A with the other floating)	Terminal B (The common combination of all like-named pins connected to terminal B)
1.	All pins except V_{PS1} 3/	All V_{PS1} pins
2.	All input and output pins	All other input-output pins

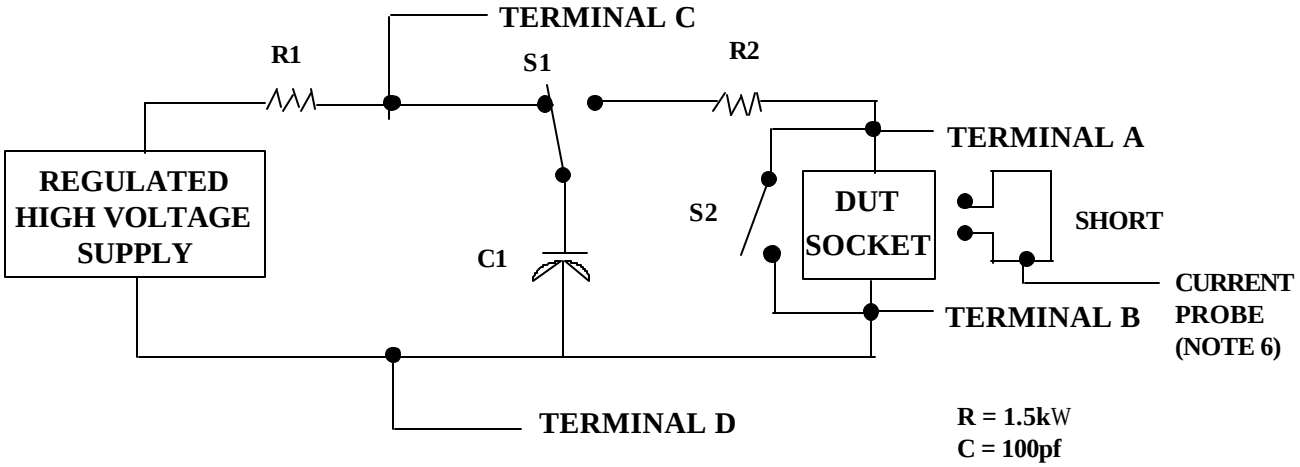
1/ Table II is restated in narrative form in 3.4 below.
2/ No connects are not to be tested.
3/ Repeat pin combination I for each named Power supply and for ground (e.g., where V_{PS1} is V_{DD}, V_{CC}, V_{SS}, V_{BB}, GND, $+V_S$, $-V_S$, V_{REF}, etc).

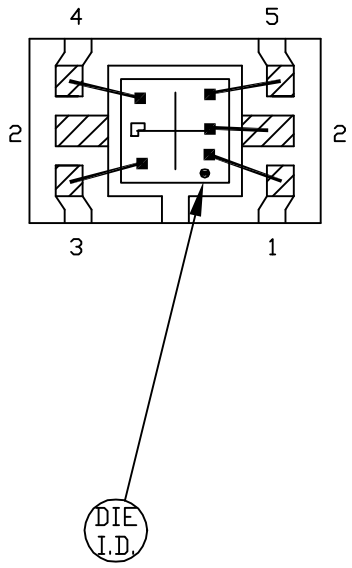
3.4 Pin combinations to be tested.

a. Each pin individually connected to terminal A with respect to the device ground pin(s) connected to terminal B. All pins except the one being tested and the ground pin(s) shall be open.

b. Each pin individually connected to terminal A with respect to each different set of a combination of all named power supply pins (e.g., V_{SS1}, or V_{SS2} or V_{SS3} or V_{CC1}, or V_{CC2}) connected to terminal B. All pins except the one being tested and the power supply pin or set of pins shall be open.

c. Each input and each output individually connected to terminal A with respect to a combination of all the other input and output pins connected to terminal B. All pins except the input or output pin being tested and the combination of all the other input and output pins shall be open.





USE NON-CONDUCTIVE EPOXY

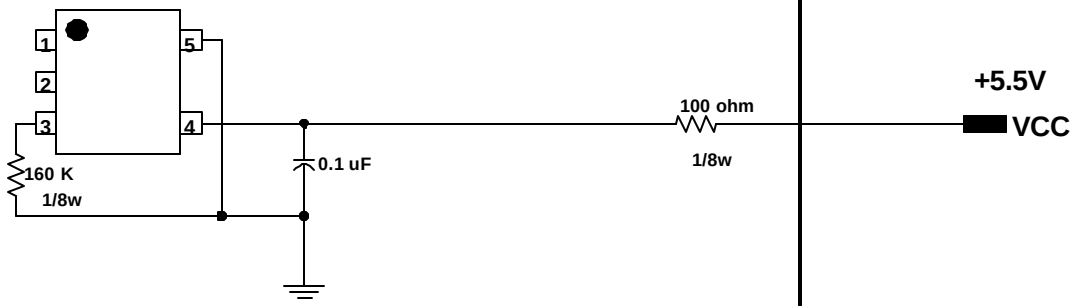
▨ BONDABLE AREA

NOTE: CAVITY DOWN

PKG. CODE: X5-1		SIGNATURES	DATE	MAXIM CONFIDENTIAL & PROPRIETARY	
CAV./PAD SIZE: 35x34	PKG.			BOND DIAGRAM #: 05-2901-0049	REV: A
	DESIGN				

ONCE PER SOCKET

ONCE PER BOARD



DEVICES: MAX6613
PACKAGE: 5-SC70
MAX. EXPECTED CURRENT = 1mA

DRAWN BY: HAK TAN

NOTES: